

**Search Notes**

Application/Control No.

10/779,379

Examiner

Anh D. Mai

Applicant(s)/Patent under  
Reexamination

CHAO, IWEN

Art Unit

2814

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST * See attached Search History	3/31/2006	A.M
IEEE Xplore: See attached Search	3/31/2006	A.M